

**Notice of References Cited**

 Application/Control No.  
 09/492,288

 Applicant(s)/Patent Under  
 Reexamination  
 YOSHIOKA ET AL.

Examiner

David Q Nguyen

 Art Unit  
 2682

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,890,061	03-1999	Timm et al.	455/321
	B	US-4,633,229	12-1986	Iacono et al.	181/144
	C	US-4,683,591	07-1987	Dawson et al.	381/58
	D	US-5,295,192	03-1994	Hamada et al.	381/71.12
	E	US-3,678,202	07-1972	Rose, Nelson J.	381/59
	F	US-6,356,641	03-2002	Warnaka et al.	381/190
	G	US-5,949,886	09-1999	Nevins et al.	381/104
	H	US-6,188,891	02-2001	Fujiki et al.	455/421
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 362067931A	03-1987	JP	Takeuchi et al.	
	O	JP 404276900A	10-1992	JP	Okano et al.	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.